

#### **General Description**

The MAX9967 dual, low-power, high-speed, pin electronics driver/comparator/load (DCL) IC includes, for each channel, a three-level pin driver, a dual comparator, variable clamps, and an active load. The driver features a wide voltage range and high-speed operation, includes high-impedance and active-termination (3rd-level drive) modes, and is highly linear even at low-voltage swings. The dual comparator provides low dispersion (timing variation) over a wide variety of input conditions. The clamps provide damping of high-speed device-undertest (DUT) waveforms when the device is configured as a high-impedance receiver. The programmable load supplies up to 35mA of source and sink current. The load facilitates contact/continuity testing, at-speed parametric testing of IOH and IOL, and pullup of high-output-impedance devices.

The MAX9967A provides tight matching of gain and offset for the drivers, and offset for the comparators and active load, allowing reference levels to be shared across multiple channels in cost-sensitive systems. Use the MAX9967B for system designs that incorporate independent reference levels for each channel.

The MAX9967 provides high-speed, differential control inputs with optional internal termination resistors that are compatible with ECL, LVPECL, LVDS, and GTL. ECL/LVPECL or flexible open-collector outputs with optional internal pullup resistors are available for the comparators. These features significantly reduce the discrete component count on the circuit board.

A 3-wire, low-voltage, CMOS-compatible serial interface programs the low-leakage, slew-rate limit, and tristate/terminate operational configurations of the MAX9967.

The MAX9967's operating range is -1.5V to +6.5V with power dissipation of only 1.15W per channel. The device is available in a 100-pin, 14mm x 14mm body, and 0.5mm pitch TQFP. An exposed 8mm x 8mm die pad on the top of the package facilitates efficient heat removal. The device is specified to operate with an internal die temperature of +70°C to +100°C, and features a die temperature monitor output.

#### **Applications**

Low-Cost Mixed-Signal/System-on-Chip ATE Commodity Memory ATE PCI or VXI Programmable Digital Instruments

#### **Features**

- **♦** Low Power Dissipation: 1.15W/Channel (typ)
- ♦ High Speed: 500Mbps at 3Vp-p
- ♦ Programmable 35mA Active-Load Current
- **♦ Low Timing Dispersion**
- ♦ Wide -1.5V to +6.5V Operating Range
- **♦** Active Termination (3rd-Level Drive)
- ♦ Low Leakage Mode: 60nA
- **♦ Integrated Clamps**
- ♦ Interfaces Easily with Most Logic Families
- **♦ Integrated PMU Connection**
- **♦ Digitally Programmable Slew Rate**
- ♦ Internal Termination Resistors
- Low Gain and Offset Error

#### **Ordering Information**

PART	TEMP RANGE	PIN-PACKAGE
MAX9967ADCCQ*	0°C to +70°C	100 TQFP-EPR**
MAX9967AGCCQ*	0°C to +70°C	100 TQFP-EPR**
MAX9967ALCCQ	0°C to +70°C	100 TQFP-EPR**
MAX9967AMCCQ*	0°C to +70°C	100 TQFP-EPR**
MAX9967AQCCQ*	0°C to +70°C	100 TQFP-EPR**
MAX9967ARCCQ*	0°C to +70°C	100 TQFP-EPR**
MAX9967BDCCQ	0°C to +70°C	100 TQFP-EPR**
MAX9967BGCCQ	0°C to +70°C	100 TQFP-EPR**
MAX9967BLCCQ	0°C to +70°C	100 TQFP-EPR**
MAX9967BMCCQ	0°C to +70°C	100 TQFP-EPR**
MAX9967BQCCQ*	0°C to +70°C	100 TQFP-EPR**
MAX9967BRCCQ	0°C to +70°C	100 TQFP-EPR**

<sup>\*</sup>Future product—contact factory for availability.

Pin Configuration and Typical Application Circuits appear at end of data sheet.

Selector Guide appears at end of data sheet.

<sup>\*\*</sup>EPR = Exposed pad reversed (TOP).

#### **ABSOLUTE MAXIMUM RATINGS**

V <sub>CC</sub> to GND	0.3V to +11.5V	DHV_ to DTV±10V
VEE to GND	7.0V to +0.3V	DLV_ to DTV±10V
V <sub>CC</sub> - V <sub>EE</sub>	0.3V to +18V	CHV_ or CLV_ to DUT±10V
GS to GND		CH_, NCH_, CL_, NCL_ to GND (open collector)2.5V to +5V
DUT_, LDH_, LDL_ to GND	2.5V to +7.5V	CH_, NCH_, CL_, NCL_ to GND (open emitter) (V <sub>CCO</sub> _ + 1.0V)
DATA_, NDATA_, RCV_, NRCV_,		All Other Pins to GND(VEE - 0.3V) to (VCC + 0.3V)
LDEN_, NLDEN_ to GND	2.5V to +5.0V	Current Out of CH_, NCH_, CL_, NCL_ (open emitter)+50mA
DATA_ to NDATA_, RCV_ to NRCV_,		DHV_, DLV_, DTV_, CHV_, CLV_,
LDEN_ to NLDEN	±1.5V	CPHV_, CPLV_ Current±10mA
V <sub>CCO</sub> to GND		TEMP Current0.5mA to +20mA
SCLK, DIN, CS, RST, TDATA_,		DUT_ Short Circuit to -1.5V to +6.5VContinuous
TRCV_, TLDEN_ to GND	1.0V to +5V	Power Dissipation ( $T_A = +70^{\circ}C$ )
DHV_, DLV_, DTV_, CHV_, CLV_, COM_,		MAX9967CCQ (derate 167mW/°C above +70°C)13.3W*
FORCE_, SENSE_ to GND	2.5V to +7.5V	Storage Temperature Range65°C to +150°C
CPHV_ to GND	2.5V to +8.5V	Junction Temperature+125°C
CPLV_ to GND	3.5V to +7.5V	Lead Temperature (soldering, 10s)+300°C
DHV_ to DLV	±10V	

<sup>\*</sup>Dissipation wattage values are based on still air with no heat sink. Actual maximum allowable power dissipation is a function of heat extraction technique and may be substantially higher.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

#### **ELECTRICAL CHARACTERISTICS**

 $(V_{CC} = +9.75V, \ V_{EE} = -5.25V, \ V_{CCO} = +2.5V, \ SC1 = SC0 = 0, \ V_{CPHV} = +7.2V, \ V_{CPLV} = -2.2V, \ V_{LDH} = V_{LDL} = 0, \ V_{GS} = 0, \ T_J = +85^{\circ}C, \ unless \ otherwise \ noted.) \ (Note 1)$ 

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
POWER SUPPLIES						
Positive Supply	Vcc		9.5	9.75	10.5	V
Negative Supply	VEE		-6.5	-5.25	-4.5	V
		$V_{LDH} = V_{LDL} = 0$		120	155	
Positive Supply Current (Note 2)	Icc	V <sub>LDH</sub> _ = V <sub>LDL</sub> _ = 3.5V, load enabled, driver = high impedance		220	255	mA
		$V_{LDH} = V_{LDL} = 0$		-220	-265	
Negative Supply Current (Note 2)	I <sub>EE</sub>	V <sub>LDH</sub> _ = V <sub>LDL</sub> _ = 3.5V, load enabled, driver = high impedance		-320	-365	mA
Power Dissipation	PD	(Notes 2, 3)		2.3	2.9	W
DUT_ CHARACTERISTICS						
Operating Voltage Range	V <sub>DUT</sub>	(Note 4)	-1.5		+6.5	V
Leakage Current in High-	lour	LLEAK = 0; $0 \le V_{DUT} \le 3V$			±1.5	μΑ
Impedance Mode	IDUT	LLEAK = 0; $V_{DUT}$ = -1.5V, +6.5V			±3	μΑ
		LLEAK = 1; $0 \le V_{DUT} \le 3V$ , $T_{J} < +90^{\circ}C$			±60	
		LLEAK = 1; $V_{DUT}$ = -1.5V, +6.5V; $T_{J}$ < +90°C			±110	
Leakage Current in Low-Leakage Mode		LLEAK = 1; $0 \le V_{DUT} \le 3V$ , $V_{LDL} = V_{LDH} = 3.5V$ ; $T_{J} < +90^{\circ}C$			±80	nA
		LLEAK = 1; V <sub>DUT</sub> = -1.5V, +6.5V; V <sub>LDL</sub> = V <sub>LDH</sub> = 3.5V; T <sub>J</sub> < +90°C			±160	

#### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{CC} = +9.75V, \ V_{EE} = -5.25V, \ V_{CCO} = +2.5V, \ SC1 = SC0 = 0, \ V_{CPHV} = +7.2V, \ V_{CPLV} = -2.2V, \ V_{LDH} = V_{LDL} = 0, \ V_{GS} = 0, \ T_{J} = +85^{\circ}C, \ unless \ otherwise \ noted.) \ (Note 1)$ 

Combined Capacitance  CDUT  Driver in term mode (DUT_ = DTV_) Driver in high-impedance mode  (Notes 5, 6)  Low-Leakage Disable Time  (Notes 6, 7)  Time to return to the specified maximum leakage after a 3V, 4V/ns step at DUT_  LEVEL PROGRAMMING INPUTS (DHV_, DLV_, DTV_, CHV_, CLV_, CPHV_, CPLV_, COM_ Input Bias Current  Settling time  To 0.1% of full-scale change (Note 7)  DIFFERENTIAL CONTROL INPUTS (DATA_, NDATA_, RCV_, NRCV_, LDEN_, NLDEN_)  Input High Voltage  VIH Input Low Voltage  VIL Differential Input Voltage  Input Bias Current  MAX9967_DCCQ, MAX9967_MCCQ  Input Termination Voltage  VTDATA_, VTRCV_, MAX9967_GCCQ, MAX9967_LCCQ, and MAX9967_CCCQ, MAX9967_LCCQ, and MAX9967_DCCQ, MAX9967_LCCQ, and MAX9967_DCCQ.	, LDH_, L	4.0 8.0 20 20 4		pF µs µs
Low-Leakage Enable Time (Notes 5, 6)  Low-Leakage Disable Time (Notes 6, 7)  Low-Leakage Recovery Time to return to the specified maximum leakage after a 3V, 4V/ns step at DUT_  LEVEL PROGRAMMING INPUTS (DHV_, DLV_, DTV_, CHV_, CLV_, CPHV_, CPLV_, COM_ Input Bias Current IBIAS  Settling time To 0.1% of full-scale change (Note 7)  DIFFERENTIAL CONTROL INPUTS (DATA_, NDATA_, RCV_, NRCV_, LDEN_, NLDEN_)  Input High Voltage VIH Input Low Voltage VIL Differential Input Voltage VDIFF  Input Bias Current MAX9967_DCCQ, MAX9967_MCCQ  Input Tarmination Voltage VTDATA_, MAX9967_GCCQ, MAX9967_LCCQ, and	, LDH_, L	20 20 4		μs
Low-Leakage Disable Time  Low-Leakage Recovery  Time to return to the specified maximum leakage after a 3V, 4V/ns step at DUT_  LEVEL PROGRAMMING INPUTS (DHV_, DLV_, DTV_, CHV_, CLV_, CPHV_, CPLV_, COM_ Input Bias Current  IBIAS  Settling time  To 0.1% of full-scale change (Note 7)  DIFFERENTIAL CONTROL INPUTS (DATA_, NDATA_, RCV_, NRCV_, LDEN_, NLDEN_)  Input High Voltage  VIH Input Low Voltage  VIL Differential Input Voltage  Input Bias Current  MAX9967_DCCQ, MAX9967_MCCQ  VTDATA_, MAX9967_GCCQ, MAX9967_LCCQ, and	, LDH_, L	20		
Low-Leakage Recovery  Time to return to the specified maximum leakage after a 3V, 4V/ns step at DUT_  LEVEL PROGRAMMING INPUTS (DHV_, DLV_, DTV_, CHV_, CLV_, CPHV_, CPLV_, COM_ Input Bias Current  IBIAS  Settling time  To 0.1% of full-scale change (Note 7)  DIFFERENTIAL CONTROL INPUTS (DATA_, NDATA_, RCV_, NRCV_, LDEN_, NLDEN_)  Input High Voltage  VIH  Input Low Voltage  VIL  Differential Input Voltage  Input Bias Current  MAX9967_DCCQ, MAX9967_MCCQ  VTDATA_, MAX9967_GCCQ, MAX9967_LCCQ, and	, LDH_, L	4		μs
LEVEL PROGRAMMING INPUTS (DHV_, DLV_, DTV_, CHV_, CPHV_, CPLV_, COM_ Input Bias Current IBIAS  Settling time To 0.1% of full-scale change (Note 7)  DIFFERENTIAL CONTROL INPUTS (DATA_, NDATA_, RCV_, NRCV_, LDEN_, NLDEN_)  Input High Voltage VIH Input Low Voltage VIL  Differential Input Voltage VDIFF  Input Bias Current MAX9967_DCCQ, MAX9967_MCCQ  Input Termination Voltage VTDATA_, MAX9967_GCCQ, MAX9967_LCCQ, and	, LDH_, L			
Input Bias Current  Settling time  To 0.1% of full-scale change (Note 7)  DIFFERENTIAL CONTROL INPUTS (DATA_, NDATA_, RCV_, NRCV_, LDEN_, NLDEN_)  Input High Voltage  VIH  Input Low Voltage  VIL  Differential Input Voltage  Input Bias Current  MAX9967_DCCQ, MAX9967_MCCQ  VTDATA_, VTDATA_, VAX9967_GCCQ, MAX9967_LCCQ, and	, LDH_, L	DL )		μs
Settling time  To 0.1% of full-scale change (Note 7)  DIFFERENTIAL CONTROL INPUTS (DATA_, NDATA_, RCV_, NRCV_, LDEN_, NLDEN_)  Input High Voltage  VIH  Input Low Voltage  VIL  Differential Input Voltage  Input Bias Current  VTDATA_,  VT		,		
DIFFERENTIAL CONTROL INPUTS (DATA_, NDATA_, RCV_, NRCV_, LDEN_, NLDEN_)  Input High Voltage			±25	μΑ
Input High Voltage  VIH  Input Low Voltage  VIL  Differential Input Voltage  Input Bias Current  VTDATA_,		1		μs
Input Low Voltage  VIL  Differential Input Voltage  Input Bias Current  MAX9967_DCCQ, MAX9967_MCCQ  VTDATA_, VT				
Differential Input Voltage  Input Bias Current  MAX9967_DCCQ, MAX9967_MCCQ  VTDATA_,  VTDATA_,  MAX9967_GCCQ, MAX9967_LCCQ, and	-1.6		+3.5	٧
Input Bias Current  MAX9967_DCCQ, MAX9967_MCCQ  VTDATA_, MAX9967_GCCQ, MAX9967_LCCQ, and	-2.0		+3.1	V
VTDATA_, MAX9967_GCCQ, MAX9967_LCCQ, and	±0.15		±1.0	V
Input Termination Valtage WAX9907_GCCQ, WAX9907_LCCQ, and			±25	μΑ
VIRCV_, VILDEN_ MAX9967_QCCQ	-2.1		+3.5	٧
Input Termination Resistor  MAX9967_GCCQ, MAX9967_LCCQ, and MAX9967_QCCQ, between signal and corresponding termination voltage input	48		52	Ω
SINGLE-ENDED CONTROL INPUTS (CS, SCLK, DIN, RST)				
Internal Threshold Reference VTHRINT	1.05	1.25	1.45	V
Internal Reference Output Rosistance		20		kΩ
External Threshold Reference V <sub>THR</sub>	0.43		1.73	V
Input High Voltage VIH	V <sub>THR</sub> + 0.2		3.5	V
Input Low Voltage V <sub>IL</sub>	-0.1		V <sub>THR</sub> - 0.2	V
Input Bias Current I <sub>B</sub>			±25	μΑ
SERIAL INTERFACE TIMING (Figure 6)			!	
SCLK Frequency fSCLK			50	MHz
SCLK Pulse-Width High t <sub>CH</sub>	8			ns
SCLK Pulse-Width Low t <sub>CL</sub>			-	
CS Low to SCLK High Setup t <sub>CSS0</sub>	8			ns
CS High to SCLK High Setup t <sub>CSS1</sub>	3.5			ns ns

### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{CC} = +9.75V, \ V_{EE} = -5.25V, \ V_{CCO} = +2.5V, \ SC1 = SC0 = 0, \ V_{CPHV} = +7.2V, \ V_{CPLV} = -2.2V, \ V_{LDH} = V_{LDL} = 0, \ V_{GS} = 0, \ T_{J} = +85^{\circ}C, \ unless \ otherwise \ noted. \ All \ temperature \ coefficients \ are \ measured \ at \ T_{J} = +70^{\circ}C \ to \ +100^{\circ}C, \ unless \ otherwise \ noted.) \ (Note 1)$ 

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNITS
SCLK High to CS High Hold	tCSH1			3.5			ns
DIN to SCLK High Setup	tDS			3.5			ns
DIN to SCLK High Hold	tDH			3.5			ns
CS Pulse Width High	tcswh			20			ns
TEMPERATURE MONITOR (TEM	P)						
Nominal Voltage		$T_J = +70^{\circ}C, R_L \ge 10M\Omega$			3.43		V
Temperature Coefficient					+10		mV/°C
Output Resistance					15		kΩ
DRIVERS (Note 8)							
DC OUTPUT CHARACTERISTICS	6 (R <sub>L</sub> ≥ 10MΩ	)					
DHV_, DLV_, DTV_, Output Offset Voltage	Vos	At DUT_ with V <sub>DHV</sub> _, V <sub>DTV</sub> _, V <sub>DLV</sub> _ independently tested	MAX9967A			±15	mV
<b>9</b>		at +1.5V	at +1.5V MAX9967B			±100	
DHV_, DLV_, DTV_, Output Offset Temperature Coefficient					±65		μV/°C
DHV_, DLV_, DTV_, Gain	Av	Measured with V <sub>DHV</sub> , V <sub>DLV</sub> , and V <sub>DTV</sub> at 0 and 4.5V	MAX9967A (Note 9)	0.999	1.00	1.001	V/V
		MAX9967B	0.96		1.001		
DHV_, DLV_, DTV_, Gain Temperature Coefficient					-35		ppm/°C
		V <sub>DUT</sub> = 1.5V, 3V (Note 10)				±5	.,
Linearity Error		Full range (Notes 10, 11)				±15	mV
DHV_ to DLV_ Crosstalk		V <sub>DLV</sub> = 0; V <sub>DHV</sub> = 200mV, 6.5V				±2	mV
DLV_ to DHV_ Crosstalk		V <sub>DHV</sub> = 5V; V <sub>DLV</sub> = -1.5V, +4.8V				±2	mV
DTV_ to DLV_ and DHV_ Crosstalk		V <sub>DHV</sub> = 3V; V <sub>DLV</sub> = 0; V <sub>DTV</sub> = -1.5V, +6.5V				±2	mV
DHV_ to DTV_ Crosstalk		V <sub>DTV</sub> _ = 1.5V; V <sub>DLV</sub> _ = 0; V <sub>DHV</sub> _ = 1.6V, 3V				±3	mV
DLV_ to DTV_ Crosstalk		V <sub>DTV</sub> _ = 1.5V; V <sub>DHV</sub> _ = 3V; V <sub>DI</sub>	LV_ = 0, 1.4V			±3	mV
DHV_, DTV_, DLV_ DC Power- Supply Rejection Ratio	PSRR	(Note 12)		40			dB
Maximum DC Drive Current	I <sub>DUT</sub> _			±60		±120	mA
DC Output Resistance	R <sub>DUT</sub> _	I <sub>DUT</sub> _ = ±30mA (Note 13)		49	50	51	Ω
DC Output Resistance Variation		$I_{DUT} = \pm 1$ mA to $\pm 8$ mA			0.5		Ω
DO Output Hesistance Valiation	∆R <sub>DUT</sub> _	$I_{DUT}$ = ±1mA to ±40mA			1	2.5	32

#### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{CC} = +9.75V, \ V_{EE} = -5.25V, \ V_{CCO} = +2.5V, \ SC1 = SC0 = 0, \ V_{CPHV} = +7.2V, \ V_{CPLV} = -2.2V, \ V_{LDH} = V_{LDL} = 0, \ V_{GS} = 0, \ T_{J} = +85^{\circ}C, \ unless \ otherwise \ noted.) \ (Note 1)$ 

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Sense Resistance	RSENSE		7.50	10	13.75	kΩ
Force Resistance	RFORCE		320	400	500	Ω
Force Capacitance	CFORCE			2		pF
DYNAMIC OUTPUT CHARACTER	RISTICS (Z <sub>L</sub> =	: 50Ω)				
		$V_{DLV} = 0, V_{DHV} = 0.1V$		30		
Drive-Mode Overshoot		V <sub>DLV</sub> _ = 0, V <sub>DHV</sub> _ = 1V		40		mV
		$V_{DLV} = 0$ , $V_{DHV} = 3V$		50		
Term-Mode Overshoot		(Note 14)		0		mV
Settling Time to Within 25mV		3V step (Note 15)		10		ns
Settling Time to Within 5mV		3V step (Note 15)		20		ns
TIMING CHARACTERISTICS (ZL	= 50Ω) (Note	16)	•			
Prop Delay, Data to Output	tpdd			2.2		ns
Prop Delay Match, t <sub>LH</sub> vs. t <sub>HL</sub>		3V <sub>P-P</sub>		±50		ps
Prop Delay Match, Drivers Within Package		(Note 17)		40		ps
Prop Delay Temperature Coefficient				+3		ps/°C
Prop Delay Change vs. Pulse Width		3V <sub>P-P</sub> , 40MHz, 2.5ns to 22.5ns pulse width, relative to 12.5ns pulse width		±60		ps
Prop Delay Change vs. Common- Mode Voltage		V <sub>DHV</sub> V <sub>DLV</sub> _ = 1V, V <sub>DHV</sub> _ = 0 to 6V		85		ps
Prop Delay, Drive to High Impedance	t <sub>PDDZ</sub>	V <sub>DHV</sub> _ = 1.0V, V <sub>DLV</sub> _ = -1.0V, V <sub>DTV</sub> _ = 0		3.2		ns
Prop Delay, High Impedance to Drive	tPDZD	V <sub>DHV</sub> _ = 1.0V, V <sub>DLV</sub> _ = -1.0V, V <sub>DTV</sub> _ = 0		3.3		ns
Prop Delay, Drive to Term	tpddt	V <sub>DHV</sub> = 3V, V <sub>DLV</sub> = 0, V <sub>DTV</sub> = 1.5V		2.5		ns
Prop Delay, Term to Drive	tPDTD	V <sub>DHV</sub> = 3V, V <sub>DLV</sub> = 0, V <sub>DTV</sub> = 1.5V		2.2		ns
DYNAMIC PERFORMANCE (Z <sub>L</sub> =	50Ω)					
		0.2V <sub>P-P,</sub> 20% to 80%		370		
D: 15 "T:		1V <sub>P-P</sub> , 10% to 90%		630		ps
Rise and Fall Time	t <sub>R</sub> , t <sub>F</sub>	3V <sub>P-P,</sub> 10% to 90%	1.0	1.3	1.5	
		5V <sub>P-P,</sub> 10% to 90%		2.0		ns
Rise and Fall Time Match	t <sub>R</sub> vs. t <sub>F</sub>	3V <sub>P-P</sub> , 10% to 90%		±0.03		ns
SC1 = 0, SC0 = 1 Slew Rate		Percent of full speed (SC0 = SC1 = 0), 3V <sub>P-P</sub> , 20% to 80%		75		%
SC1 = 1, SC0 = 0 Slew Rate		Percent of full speed (SC0 = SC1 = 0), 3V <sub>P-P</sub> , 20% to 80%		50		%
SC1 = 1, SC0 = 1 Slew Rate		Percent of full speed (SC0 = SC1 = 0), 3V <sub>P-P</sub> , 20% to 80%		25		%



### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{CC} = +9.75V, V_{EE} = -5.25V, V_{CCO} = +2.5V, SC1 = SC0 = 0, V_{CPHV} = +7.2V, V_{CPLV} = -2.2V, V_{LDH} = V_{LDL} = 0, V_{GS} = 0, V_{TJ} = +85^{\circ}C$ , unless otherwise noted. All temperature coefficients are measured at  $T_{J} = +70^{\circ}C$  to  $+100^{\circ}C$ , unless otherwise noted.) (Note 1)

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNITS
		0.2V <sub>P-P</sub>			650		ps
Minimum Pulse Width		1V <sub>P-P</sub>			1.0		
(Note 18)		3V <sub>P-P</sub>			2.0		ns
		5V <sub>P-P</sub>			2.9		
		0.2V <sub>P-P</sub>			1700		
Data Data (Nata 10)		1V <sub>P-P</sub>			1000		Mlana
Data Rate (Note 19)		3V <sub>P-P</sub>			500		Mbps
		5V <sub>P-P</sub>			350		
Dynamic Crosstalk		(Note 20)			10		mV <sub>P-P</sub>
Rise and Fall Time, Drive to Term	t <sub>DTR</sub> , t <sub>DTF</sub>	V <sub>DHV</sub> = 3V, V <sub>DLV</sub> = 0, V <sub>DTV</sub> 10% to 90%, Figure 1a (Note 2			1.6		ns
Rise and Fall Time, Term to Drive	t <sub>TDR</sub> , t <sub>TDF</sub>	V <sub>DHV</sub> = 3V, V <sub>DLV</sub> = 0, V <sub>DTV</sub> 10% to 90%, Figure 1b (Note 2			0.7		ns
COMPARATORS (Note 8)		,					
DC CHARACTERISTICS							
Input Voltage Range	VIN	(Note 4)		-1.5		+6.5	V
Differential Input Voltage	$V_{DIFF}$			±8			V
Hysteresis	V <sub>H</sub> YST				0		mV
	Voc	151/	MAX9967A			±20	.,
Input Offset Voltage	Vos	$V_{DUT} = 1.5V$	MAX9967B			±100	mV
Input Offset Voltage Temperature Coefficient					±50		μV/°C
		V <sub>DUT</sub> _ = 0, 3V		47	78		
Common-Mode Rejection Ratio	CMRR	V <sub>DUT</sub> _ = 0, 6.5V		54	78		dB
(Note 22)		V <sub>DUT</sub> _ = -1.5V, +6.5V		44	61		1
		V <sub>DUT</sub> _ = 1.5V, 3V				±3	
Linearity Error (Note 10)		V <sub>DUT</sub> _ = 6.5V				±5	mV
		V <sub>DUT</sub> _ = -1.5V				±25	
V <sub>CC</sub> Power-Supply Rejection Ratio (Note 12)	PSRR	V <sub>DUT</sub> _ = -1.5V, +6.5V		57	80		dB
VEE Power-Supply Rejection	2022	$V_{DUT} = 0, 6.5V$		44	64		
Ratio (Note 12)	PSRR	V <sub>DUT</sub> _ = -1.5V		33	60		dB
AC CHARACTERISTICS (Note 23	)	•					•
Minimum Pulse Width (Note 24)	tpw(MIN)	MAX9967_DCCQ, MAX9967_C MAX9967_LCCQ, MAX9967_R			0.7		ns
		MAX9967_MCCQ, MAX9967_0	QCCQ		0.85		
Prop Delay	tpDL		·		2.2		ns
Prop Delay Temperature Coefficient					+6		ps/°C

#### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{CC} = +9.75V, \ V_{EE} = -5.25V, \ V_{CCO} = +2.5V, \ SC1 = SC0 = 0, \ V_{CPHV} = +7.2V, \ V_{CPLV} = -2.2V, \ V_{LDH} = V_{LDL} = 0, \ V_{GS} = 0, \ T_{J} = +85^{\circ}C, \ unless \ otherwise \ noted.) \ (Note 1)$ 

PARAMETER	SYMBOL		CONDITIONS	}	MIN	TYP	MAX	UNITS
Prop Delay Match, High/Low vs. Low/High						±25		ps
Prop Delay Match, Comparators Within Package		(Note	(Note 17)			35		ps
Prop Delay Dispersion vs.		V <sub>CHV</sub> _	. = V <sub>CLV</sub> = 0, 6.4V			±75		200
Common-Mode Input (Note 25)		V <sub>CHV</sub> _	. = V <sub>CLV</sub> _ = -1.4V			±175		ps
Prop Delay Dispersion vs. Overdrive		100m\	/ to 1V			220		ps
Prop Delay Dispersion vs. Pulse Width			to 22.5ns pulse width, i s pulse width	relative to		±40		ps
Prop Delay Dispersion vs. Slew Rate		0.5V/n	s to 2V/ns slew rate			100		ps
Marcafa was Tuesdain at 400/ de 000/		_	$= 1.0V_{P-P}, t_{R} = t_{F} =$	Term mode		250		
Waveform Tracking 10% to 90%		· · · · ·	10% to 90% relative	High-Z mode		500		ps
OPEN-COLLECTOR LOGIC OUTI and MAX9967_RCCQ)	PUTS (CH_, I	NCH_, C	CL_, NCL_: MAX9967_	DCCQ, MAX996	7_GCCC	), MAX996	7_LCCQ	,
V <sub>CCO</sub> _ Voltage Range	Vvcco_				0		3.5	V
Output Low-Voltage Compliance		Set by	IOL, RTERM, and VCCC	)_		-0.5		V
Output High Current	Іон	MAX99	967_DCCQ, MAX9967_	_GCCQ	-0.05	0	+0.10	mA
Output Low Current	loL	MAX99	967_DCCQ, MAX9967_	_GCCQ	7.6	8	8.4	mA
Output High Voltage	V <sub>OH</sub>	- · · · -	: I <sub>NCH</sub> = I <sub>CL</sub> = I <sub>NCL</sub> 967_LCCQ, MAX9967_	•	VCCO_ - 0.05	V <sub>CCO</sub> _ - 0.005		V
Output Low Voltage	VoL		: I <sub>NCH</sub> = I <sub>CL</sub> = I <sub>NCL</sub> 967_LCCQ, MAX9967_			V <sub>CCO</sub> _ - 0.4		V
Output Voltage Swing			: I <sub>NCH</sub> = I <sub>CL</sub> = I <sub>NCL</sub> 967_LCCQ, MAX9967_		360	390	440	mV
Output Termination Resistor	R <sub>TERM</sub>	CH_, 1	-ended measurement f NCH_, CL_, NCL_, MAX 967_RCCQ		48		52	Ω
Differential Rise Time	t <sub>R</sub>	20% to 80%	MAX9967_DCCQ, MAX9967_GCCQ, R1 end of line MAX9967_LCCQ, MA			280		ps
Differential Fall Time	t <sub>F</sub>	20% to 80%	MAX9967_DCCQ, MAX9967_GCCQ, R1 end of line MAX9967_LCCQ, MA			280		ps
OPEN-EMITTER LOGIC OUTPUT	S (CH_, NCH	_, CL_,	NCL_: MAX9967_MC	CQ and MAX996	67_QCCC	2)		
V <sub>CCO</sub> _ Voltage Range	Vvcco_				-0.1		+3.5	V
V <sub>CCO</sub> _ Supply Current	lvcco_	All out	puts $50\Omega$ to (V <sub>VCCO</sub>	2V)		165		mA
	•	-						-

### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{CC} = +9.75V, V_{EE} = -5.25V, V_{CCO} = +2.5V, SC1 = SC0 = 0, V_{CPHV} = +7.2V, V_{CPLV} = -2.2V, V_{LDH} = V_{LDL} = 0, V_{GS} = 0, V_{J} = +85^{\circ}C$ , unless otherwise noted. All temperature coefficients are measured at  $T_{J} = +70^{\circ}C$  to  $+100^{\circ}C$ , unless otherwise noted.) (Note 1)

PARAMETER	SYMBOL	CONDITIONS	6	MIN	TYP	MAX	UNITS
Output High Voltage	V <sub>OH</sub>	50Ω to (V <sub>VCCO</sub> 2V)	50Ω to (V <sub>VCCO</sub> 2V)		V <sub>CCO</sub> _ - 0.85		V
Output Low Voltage	VoL	50Ω to (V <sub>VCCO</sub> 2V)			V <sub>CCO</sub> _ - 1.7	V <sub>CCO</sub> _ - 1.6	V
Output Voltage Swing		50Ω_to (V <sub>VCCO</sub> 2V)		800	850	900	mV
Differential Rise Time	t <sub>R</sub>	20% to 80%			370		ps
Differential Fall Time	tF	20% to 80%			370		ps
CLAMPS				•			
High Clamp Input Voltage Range	V <sub>CPH</sub> _			-0.3		+7.5	V
Low Clamp Input Voltage Range	V <sub>CPL</sub>			-2.5		+5.3	V
		At DUT_ with IDUT_ = 1mA, \	/CPHV_ = 0			±100	
Clamp Offset Voltage	Vos	At DUT_ with $I_{DUT} = -1mA$ ,				±100	mV
Offset Voltage Temperature Coefficient					±0.5		mV/°C
Clamp Power-Supply Rejection Ratio (Note 12)	PSRR	IDUT_ = 1mA, V <sub>CPHV_</sub> = 0 IDUT_ = -1mA, V <sub>CPLV_</sub> = 0			54 54		dB
Voltage Gain	Av			0.96		1.00	V/V
Voltage Gain Temperature Coefficient					-100		ppm/°C
Classa Linearity		I <sub>DUT</sub> = 1mA, V <sub>CPLV</sub> = -1.5 V <sub>CPHV</sub> = -0.3V to +6.5V	V,		±10		ma\/
Clamp Linearity		I <sub>DUT</sub> _= -1mA, V <sub>CPHV</sub> _ = 6.5 V <sub>CPLV</sub> _ = -1.5V to +5.3V	V,		±10		mV
	L	VCPHV_ = 0, VCPLV_ = -1.5V	, V <sub>DUT</sub> _ = 6.5V	50		95	mA
Short-Circuit Output Current	ISCDUT_	VCPHV_ = 6.5V, VCPLV_ = 5V	/, V <sub>DUT</sub> _ = -1.5V	-95		-50	mA
Clamp DC Impedance	Rout	$V_{CPHV} = 3V$ , $V_{CPLV} = 0$ , $I_{DUT} = \pm 5$ mA and $\pm 15$ mA		50		55	Ω
ACTIVE LOAD (V <sub>COM</sub> = +1.5V, F	L > 1MΩ, dri	ver in high-impedance mode	e, unless otherw	ise noted	d)		•
COM_ Voltage Range	V <sub>COM</sub> _			-1.5		+5.7	V
Differential Voltage Range		V <sub>DUT</sub> V <sub>COM</sub> _		-7.2		+8.0	V
0011 0% 177 15	.,		MAX9967A			±15	
COM_ Offset Voltage	Vos	ISOURCE = ISINK = 20mA	MAX9967B			±100	mV
Offset Voltage Temperature Coefficient					50		μV/°C
COM_ Voltage Gain	Av	V <sub>COM</sub> = 0, 4.5V, I <sub>SOURCE</sub> = I <sub>SINK</sub> = 20mA		0.98		1.00	V/V
Voltage Gain Temperature Coefficient					±25		ppm/°C

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#### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{CC} = +9.75 \text{V}, \ V_{EE} = -5.25 \text{V}, \ V_{CCO} = +2.5 \text{V}, \ SC1 = SC0 = 0, \ V_{CPHV} = +7.2 \text{V}, \ V_{CPLV} = -2.2 \text{V}, \ V_{LDH} = V_{LDL} = 0, \ V_{GS} = 0, \ T_{J} = +85 ^{\circ}\text{C}, \ \text{unless otherwise noted.} \ \text{All temperature coefficients are measured at } T_{J} = +70 ^{\circ}\text{C} \ \text{to } +100 ^{\circ}\text{C}, \ \text{unless otherwise noted.}) \ \text{(Note 1)}$ 

PARAMETER	SYMBOL	CON	DITIONS	MIN	TYP	MAX	UNITS
COM_ Linearity Error		V <sub>COM</sub> _ = -1.5V, +5.7V;   <sub>SOURCE</sub> =   <sub>SINK</sub> = 20mA (Note 10)			±3	±15	mV
COM_ Output-Voltage Power- Supply Rejection Ratio	PSRR	V <sub>COM</sub> = 2.5V, I <sub>SOURCE</sub> = I <sub>SINK</sub> = 2	20mA	40			dB
Output Resistance, Sink or	Do	with $V_{COM} = -1.5V$	ISOURCE = ISINK = $35\text{mA}$ ; VDUT_ = $3\text{V}$ , $6.5\text{V}$ with VCOM_ = $-1.5\text{V}$ and VDUT_ = $-1.5\text{V}$ , $+2\text{V}$ with VCOM_ = $5.7\text{V}$				kΩ
Source	Ro	$I_{SOURCE} = I_{SINK} = 1$ with $V_{COM} = -1.5V$ $+2V$ with $V_{COM} = 5$	_	500			kΩ
Output Resistance, Linear Region	Ro	$I_{DUT} = \pm 10$ mA, $I_{SO}$ $V_{COM} = 2.5$ V	IDUT_ = ±10mA, ISOURCE = ISINK = 35mA,		6		Ω
Deadband		V <sub>COM</sub> _ = 2.5V, 95%	ISOURCE to 95% ISINK		400	700	mV
SOURCE CURRENT (V <sub>DUT</sub> = 4.5	V)						
Maximum Source Current		V <sub>LDL</sub> = 3.8V		36		40	mA
Source Programming Gain	A <sub>TC</sub>	$V_{LDL} = 0.3V, 3V;$ $V_{LDH} = 0.1V$			10	10.1	mA/V
Source Current Offset (Combined Offset of LDL_ and GS)	I <sub>OS</sub>	V <sub>LDL</sub> = 20mV	MAX9967A (Note 9) MAX9967B	10 0		50 200	μΑ
Source Current Temperature Coefficient		ISOURCE = 35mA			-6		μΑ/°C
Source Current Power-Supply Rejection Ratio	PSRR	ISOURCE = 25mA ISOURCE = 35mA				±70 ±84	μA/V
Source Current Linearity (Note 26)		$V_{LDL} = 100$ mV, 1V $V_{LDL} = 3.5$ V	, 2.5V			±60 ±130	μΑ
SINK CURRENT (V <sub>DUT</sub> = -1.5V)							.1.
Maximum Sink Current		V <sub>LDH</sub> _ = 3.8V		-40		-36	mA
Sink Programming Gain	ATC	V <sub>LDH</sub> _ = 0.3V, 3V; V	LDL_ = 0.1V	-10.1	-10	-9.9	mA/V
Sink Current Offset (Combined Offset of LDH_ and GS)	los	V <sub>LDH</sub> _ = 20mV	MAX9967A (Note 9) MAX9967B	-50 -200		-10 0	μΑ
Sink Current Temperature Coefficient		ISINK = 35mA			+6		μΑ/°C
Sink Current Power-Supply Rejection Ratio	PSRR	ISINK = 25mA ISINK = 35mA				±70 ±84	μA /V

#### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{CC} = +9.75V, V_{EE} = -5.25V, V_{CCO} = +2.5V, SC1 = SC0 = 0, V_{CPHV} = +7.2V, V_{CPLV} = -2.2V, V_{LDH} = V_{LDL} = 0, V_{GS} = 0, V_{J} = +85^{\circ}C$ , unless otherwise noted. All temperature coefficients are measured at  $T_{J} = +70^{\circ}C$  to  $+100^{\circ}C$ , unless otherwise noted.) (Note 1)

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNITS
Sink Current Linearity		V <sub>LDH</sub> _ = 100mV, 1V, 2.5V	V <sub>LDH</sub> _ = 100mV, 1V, 2.5V			±60	
(Note 26)		V <sub>LDH</sub> _ = 3.5V				±130	μΑ
GROUND SENSE							
GS Voltage Range	V <sub>GS</sub>	Verified by GS common-mode	error test	±250			mV
OC Common Made France		$V_{DUT}$ = -1.5V, $V_{GS}$ = ±250mV = 0.1V	, V <sub>LDH</sub> V <sub>G</sub> S			±25	
GS Common-Mode Error		$V_{DUT}$ = +4.5V, $V_{GS}$ = ±250mV $V_{GS}$ = 0.1V	/, V <sub>LDL</sub>			±25	μA
GS Input Bias Current		$V_{GS} = 0$				±25	μΑ
AC CHARACTERISTICS (Z <sub>L</sub> = 50	Ω to GND)						
Enable Time (Note 27)	ten	ISOURCE = 20mA, V <sub>COM</sub> _ = -1.	5V		2.2		20
Enable Time (Note 27)	tEN	$I_{SINK} = 20$ mA, $V_{COM} = +1.5$ V			2.2		ns
Diagble Time (Note 27)	+===	ISOURCE = 20mA, V <sub>COM</sub> _ = -1.	5V		1.9		22
Disable Time (Note 27)	tDIS	$I_{SINK} = 20$ mA, $V_{COM} = +1.5$ V			1.9		ns
Current Settling Time on		ISOURCE = ISINK = 1mA and	To 10%		10		22
Commutation		35mA (Notes 7, 28)	To 1.5%		50	·	ns
Spike During Enable/Disable Transition		ISOURCE = ISINK = 35mA, VCOI	M_ = 0		100		mV

- **Note 1:** All minimum and maximum limits are 100% production tested. Tests are performed at nominal supply voltages unless otherwise noted.
- **Note 2:** Total for dual device at worst-case setting.  $R_L \ge 10M\Omega$ . The supply currents are measured with typical supply voltages.
- Note 3: Does not include internal dissipation of the comparator outputs. With output loads of 50Ω to (V<sub>VCCO</sub> 2V), this adds 120mW (typ) to the total device power (MAX9967\_MCCQ and MAX9967\_QCCQ). For MAX9967\_LCCQ, additional power dissipation is typically (32mA x V<sub>VCCO</sub>).
- Note 4: Externally forced voltages may exceed this range provided that the Absolute Maximum Ratings are not exceeded.
- Note 5: Transition time from LLEAK being asserted to leakage current dropping below specified limits.
- Note 6: Based on simulation results only.
- Note 7: Transition time from LLEAK being deasserted to output returning to normal operating mode.
- Note 8: With the exception of Offset and Gain/CMRR tests, reference input values are calibrated for offset and gain.
- **Note 9:** Measured at  $V_{CC} = +9.75$ ,  $V_{EE} = -5.25V$ , and  $T_{J} = +85^{\circ}C$ .
- Note 10: Relative to straight line between 0 and 4.5V.
- Note 11: Specifications measured at the end points of the full range. Full ranges are -1.3V ≤ V<sub>DHV</sub>\_ ≤ 6.5V, -1.5V ≤ V<sub>DLV</sub>\_ ≤ 6.3V, -1.5V ≤ V<sub>DTV</sub> ≤ 6.5V.
- Note 12: Change in offset voltage with power supplies independently set to their minimum and maximum values.
- **Note 13:** Nominal target value is  $50\Omega$ . Contact factory for alternate trim selections within the  $45\Omega$  to  $51\Omega$  range.
- Note 14: V<sub>DTV</sub> = +1.5V, R<sub>S</sub> = 50Ω. External signal driven into T-line is a 0 to +3V edge with 1.2ns rise time (10% to 90%). Measurement is made using the comparator.
- Note 15: Measured from the crossing point of DATA\_ inputs to the settling of the driver output.
- **Note 16:** Prop delays are measured from the crossing point of the differential input signals to the 50% point of the expected output swing. Rise time of differential inputs DATA\_ and RCV\_ is 250ps (10% to 90%).
- Note 17: Rising edge to rising edge or falling edge to falling edge.
- Note 18: Specified amplitude is programmed. At this pulse width, the output reaches at least 95% of its nominal (DC) amplitude. The pulse width is measured at DATA\_.

#### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{CC} = +9.75V, V_{EE} = -5.25V, V_{CCO} = +2.5V, SC1 = SC0 = 0, V_{CPHV} = +7.2V, V_{CPLV} = -2.2V, V_{LDH} = V_{LDL} = 0, V_{GS} = 0, T_{J} = +85^{\circ}C$ , unless otherwise noted. All temperature coefficients are measured at  $T_{J} = +70^{\circ}C$  to  $+100^{\circ}C$ , unless otherwise noted.) (Note 1)

- **Note 19:** Specified amplitude is programmed. Maximum data rate is specified in transitions per second. A square wave that reaches at least 95% of its programmed amplitude may be generated at one-half this frequency.
- Note 20: Crosstalk from either driver to the other. Aggressor channel is driving 3V<sub>P-P</sub> into a 50Ω load. Victim channel is in term mode with V<sub>DTV</sub> = +1.5V.
- Note 21: Indicative of switching speed from DHV\_ or DLV\_ to DTV\_ and DTV\_ to DHV\_ or DLV\_ when  $V_{DLV} < V_{DTV} < V_{DHV}$ . If  $V_{DTV} < V_{DLV}$  or  $V_{DTV} > V_{DHV}$ , switching speed is degraded by approximately a factor of 3.
- Note 22: Change in offset voltage over the input range.
- Note 23: Unless otherwise noted, all propagation delays are measured at 40MHz, V<sub>DUT</sub> = 0 to +2V, V<sub>CHV</sub> = V<sub>CLV</sub> = +1V, slew rate = 2V/ns, Z<sub>S</sub> = 50Ω, driver in term mode with V<sub>DTV</sub> = 0. Comparator outputs are terminated with 50Ω to GND at scope input with V<sub>CCO</sub> = 2V. Open-collector outputs are also terminated (internally or externally) with R<sub>TERM</sub> = 50Ω to V<sub>CCO</sub>. Measured from V<sub>DUT</sub> crossing calibrated CHV\_/CLV\_ threshold to crossing point of differential outputs.
- Note 24: V<sub>DUT</sub> = 0 to +1V, V<sub>CHV</sub> = V<sub>CLV</sub> = +0.5V. At this pulse width, the output reaches at least 90% of its DC voltage swing. The pulse width is measured at the crossing points of the differential outputs.
- Note 25: Relative to propagation delay at V<sub>CHV</sub> = V<sub>CLV</sub> = +1.5V. V<sub>DUT</sub> = 200mV<sub>P-P</sub>. Overdrive = 100mV.
- Note 26: Relative to segmented interpolations between 20mV, 200mV, 2V, and 3V.
- Note 27: Measured from the crossing point of LDEN\_ inputs to the 10% point of the output voltage change.
- Note 28:  $V_{COM}$  = 1.5V,  $R_{S}$  = 50 $\Omega$ , driving voltage = +4V to -1V transition and -1V to +4V transition. Settling time is measured from  $V_{DUT}$  = 1.5V to  $I_{SINK}/I_{SOURCE}$  settling within specified tolerance.

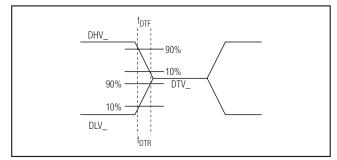


Figure 1a. Drive to Term Rise and Fall Time

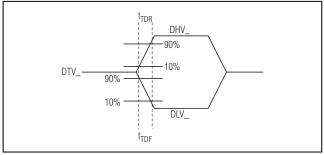
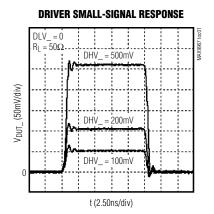
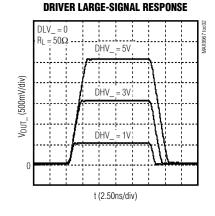
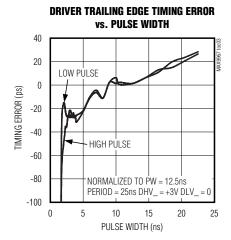


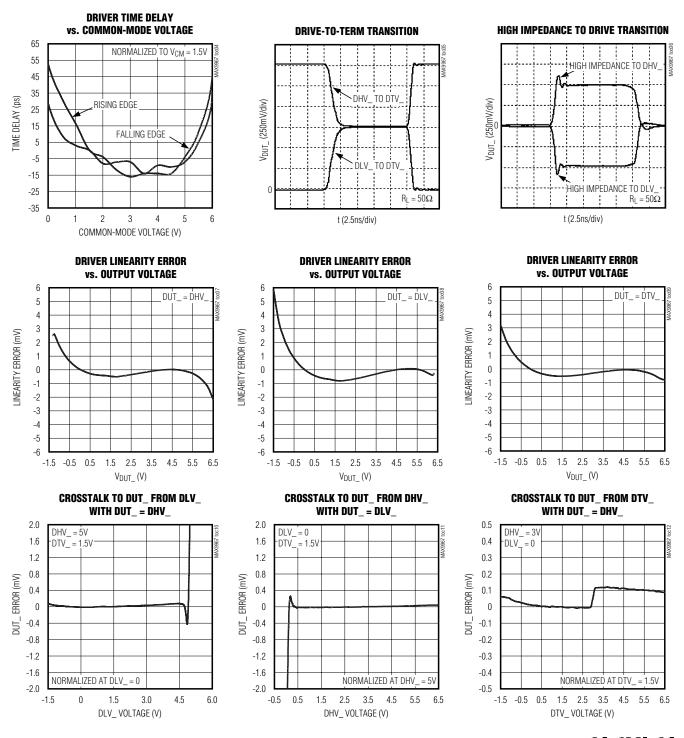
Figure 1b. Term to Drive Rise and Fall Time

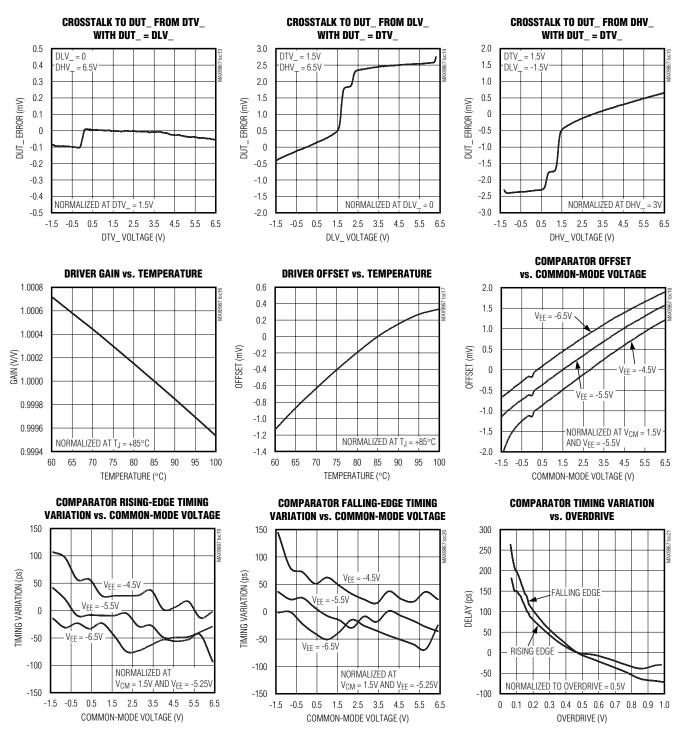
### Typical Operating Characteristics

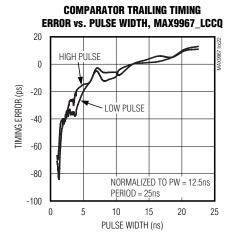


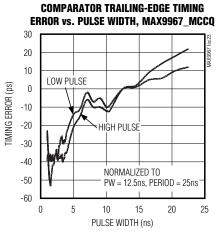


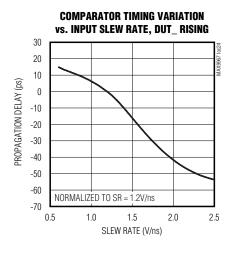


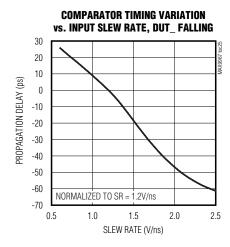


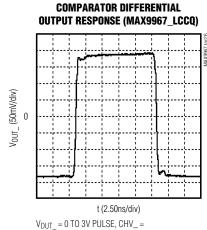


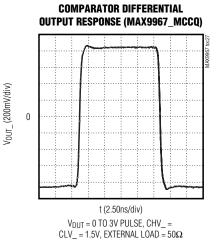


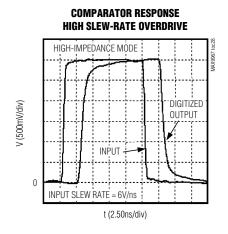


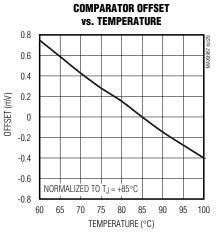


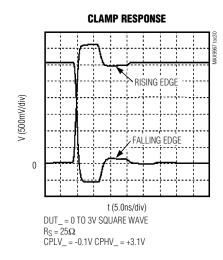


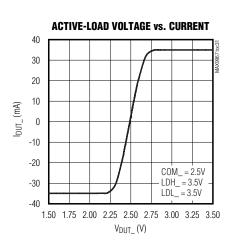


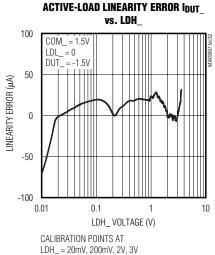


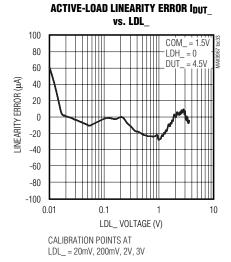


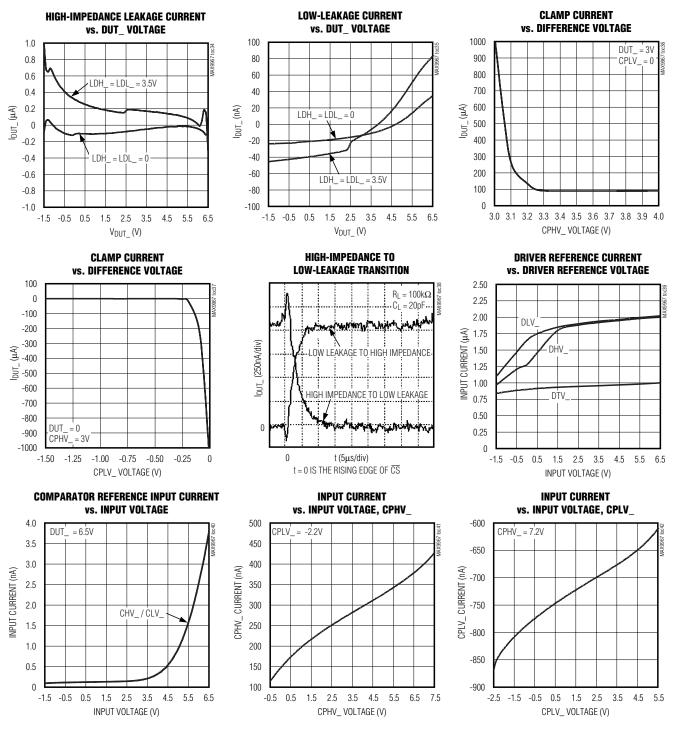




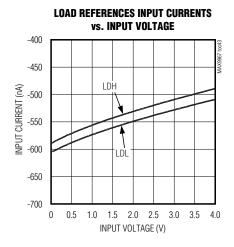


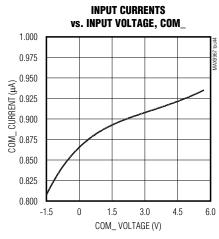


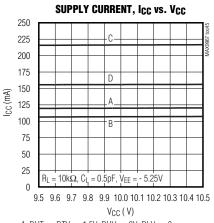




#### Typical Operating Characteristics (continued)





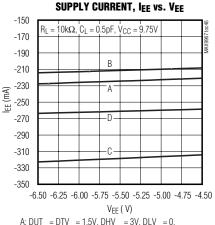


I<sub>SOURCE</sub> = I<sub>SINK</sub> = 0

B: SAME AS A EXCEPT DRIVER DISABLED HIGH-Z AND LOAD ENABLED

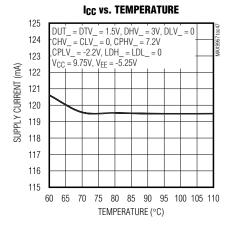
C: SAME AS B EXCEPT  $I_{SOURCE} = I_{SINK} = 35 \text{mA}$ 

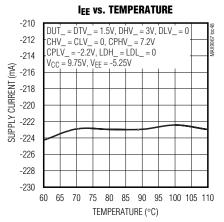
D: SAME AS C EXCEPT LOW-LEAKAGE MODE ASSERTED





C: SAME AS B EXCEPT  $I_{SOURCE} = I_{SINK} = 35$ mA D: SAME AS C EXCEPT LOW-LEAKAGE MODE ASSERTED





LOAD ENABLED

### Pin Description

PIN	NAME	FUNCTION
1	TEMP	Temperature Monitor Output
2, 9, 12, 14, 17, 24, 35, 45, 46, 60, 80, 81, 91	VEE	Negative Power-Supply Input
3, 5, 10, 16, 21, 23, 25, 34, 43, 44, 82, 83, 92	GND	Ground Connection
4, 11, 15, 22, 33, 41, 42, 66, 84, 85, 93	Vcc	Positive Power-Supply Input
6	FORCE1	Channel 1 Force Input from External PMU
7	DUT1	Channel 1 Device-Under-Test Input/Output. Combined I/O for driver, comparator, clamp, and load.
8	SENSE1	Channel 1 Sense Output to External PMU
13	GS	Ground Sense. GS is the ground reference for LDH_ and LDL
18	SENSE2	Channel 2 Sense Output to External PMU
19	DUT2	Channel 2 Device-Under-Test Input/Output. Combined I/O for driver, comparator, clamp, and load.
20	FORCE2	Channel 2 Force Input from External PMU
26	CLV2	Channel 2 Low Comparator Reference Input
27	CHV2	Channel 2 High Comparator Reference Input
28	DLV2	Channel 2 Driver Low Reference Input
29	DTV2	Channel 2 Driver Termination Reference Input
30	DHV2	Channel 2 Driver High Reference Input
31	CPLV2	Channel 2 Low-Clamp Reference Input
32	CPHV2	Channel 2 High-Clamp Reference Input
36	NCH2	Channel 2 Comparator High Output Differential output of channel 2 high comparator
37	CH2	Channel 2 Comparator High Output. Differential output of channel 2 high comparator.
38	V <sub>CCO2</sub>	Channel 2 Collector Voltage Input. Voltage for channel 2 comparator output pullup resistors. For open-collector outputs, this is the pullup voltage for the internal termination resistors. For open-emitter outputs, this is the collector voltage of the output transistors. Not internally connected on open-collector versions without internal termination resistors.
39	NCL2	Channel 2 Comparator Law Output Differential output of channel 2 law comparator
40	CL2	Channel 2 Comparator Low Output. Differential output of channel 2 low comparator.
47	COM2	Channel 2 Active-Load Commutation Voltage Reference Input
48	LDL2	Channel 2 Active-Load Source Current Reference Input
49	LDH2	Channel 2 Active-Load Sink Current Reference Input
50, 76	N.C.	No Connect. Make no connection.
51	TDATA2	Channel 2 Data Termination Voltage Input. Termination voltage input for the DATA2 and NDATA2 differential inputs. Not internally connected on versions without internal termination resistors.
52	NDATA2	Channel 2 Multiplexer Control Inputs. Differential controls DATA2 and NDATA2 select driver 2's
53	DATA2	input from DHV2 or DLV2. Drive DATA2 above NDATA2 to select DHV2. Drive NDATA2 above DATA2 to select DLV2.

### Pin Description (continued)

PIN	NAME	FUNCTION			
54	TRCV2	Channel 2 RCV Termination Voltage Input. Termination voltage input for the RCV2 and NRCV2 differential inputs. Not internally connected on versions without internal termination resistors.			
55	NRCV2	Channel 2 Multiplexer Control Inputs. Differential controls RCV2 and NRCV2 place channel 2 into			
56	RCV2	receive mode. Drive RCV2 above NRCV2 to place channel 2 into receive mode. Drive NRCV2 above RCV2 to place channel 2 into drive mode.			
57	TLDEN2	Channel 2 Load Enable Termination Voltage Input. Termination voltage input for the LDEN2 and NLDEN2 differential inputs. Not internally connected on versions without internal termination resistors.			
58	NLDEN2	Channel 2 Multiplexer Control Inputs. Differential controls LDEN2 and NLDEN2 enable/disable the			
59	LDEN2	ive load. Drive LDEN2 above NLDEN2 to enable the channel 2 active load. Drive NLDEN2 above EN2 to disable the channel 2 active load.			
61	RST	Reset Input. Asynchronous reset input for the serial register. $\overline{RST}$ is active low and asserts low-leakage mode. At power-up, hold $\overline{RST}$ low until V <sub>CC</sub> and V <sub>EE</sub> have stabilized.			
62	CS	Chip-Select Input. Serial port activation input. CS is active low.			
63	THR	Single-Ended Logic Threshold. Leave THR unconnected to set the threshold to +1.25V or force THR to a desired threshold voltage.			
64	SCLK	Serial-Clock Input. Clock for serial port.			
65	DIN	Data Input. Serial port data input.			
67	LDEN1	Channel 1 Multiplexer Control Inputs. Differential controls LDEN1 and NLDEN1 enable/disable the			
68	NLDEN1	active load. Drive LDEN1 above NLDEN1 to enable the channel 1 active load. Drive NLDEN1 above LDEN1 to disable the channel 1 active load.			
69	TLDEN1	Channel 1 Load Enable Termination Voltage Input. Termination voltage input for the LDEN1 and NLDEN1 differential inputs. Not internally connected on versions without internal termination resistors.			
70	RCV1	Channel 1 Multiplexer Control Inputs. Differential controls RCV1 and NRCV1 place channel 1 into			
71	NRCV1	receive mode. Drive RCV1 above NRCV1 to place channel 1 into receive mode. Drive NRCV1 above RCV1 to place channel 1 into drive mode.			
72	TRCV1	Channel 1 RCV Termination Voltage Input. Termination voltage input for the RCV1 and NRCV1 differential inputs. Not internally connected on versions without internal termination resistors.			
73	DATA1	Channel 1 Multiplexer Control Inputs. Differential controls DATA1 and NDATA1 select driver 1's			
74	NDATA1	input from DHV1 or DLV1. Drive DATA1 above NDATA1 to select DHV1. Drive NDATA1 above DATA1 to select DLV1.			
75	TDATA1	Channel 1 Data Termination Voltage Input. Termination voltage input for the DATA1 and NDATA1 differential inputs. Not internally connected on versions without internal termination resistors.			
77	LDH1	Channel 1 Active-Load Sink Current Reference Input			
78	LDL1	Channel 1 Active-Load Source Current Reference Input			
79	COM1	Channel 1 Active Load Commutation Voltage Reference Input			
86	CL1	Channel 1 Low Comparator Output. Differential output of channel 1 low comparator.			
87	NCL1	onamion i zow domparator duput. Dinorditial duput of chariller i low comparator.			

#### Pin Description (continued)

PIN	NAME	FUNCTION					
88	VcCO1	Channel 1 Collector Voltage Input. Voltage for channel 1 comparator output pullup resistors. For open-collector outputs, this is the pullup voltage for the internal termination resistors. For open-emitter outputs, this is the collector voltage of the output transistors. Not internally connected on open-collector versions without internal termination resistors.					
89	CH1	Channel 1 High Comparator High Output Differential output of channel 1 high side comparator					
90	NCH1	Channel 1 High Comparator High Output. Differential output of channel 1 high-side comparator.					
94	CPHV1	Channel 1 High-Clamp Reference Input					
95	CPLV1	Channel 1 Low-Clamp Reference Input					
96	DHV1	Channel 1 Driver High Reference Input					
97	DTV1	Channel 1 Driver Termination Reference Input					
98	DLV1	Channel 1 Driver Low Reference Input					
99	CHV1	Channel 1 High-Comparator Reference Input					
100	CLV1	Channel 1 Low-Comparator Reference Input					

#### **Detailed Description**

The MAX9967 dual, low-power, high-speed, pin electronics DCL IC includes, for each channel, a three-level pin driver, a dual comparator, variable clamps, and an active load. The driver features a -1.5V to +6.5V operating range and high-speed operation, includes highimpedance and active-termination (3rd-level drive) modes, and is highly linear even at low voltage swings. The dual comparator provides low dispersion (timing variation) over a wide variety of input conditions. The clamps provide damping of high-speed DUT\_ waveforms when the device is configured as a high-impedance receiver. The programmable load supplies up to 35mA of source and sink current. The load facilitates contact/continuity testing, at-speed parametric testing of IOH and IOL, and pullup of high output-impedance devices.

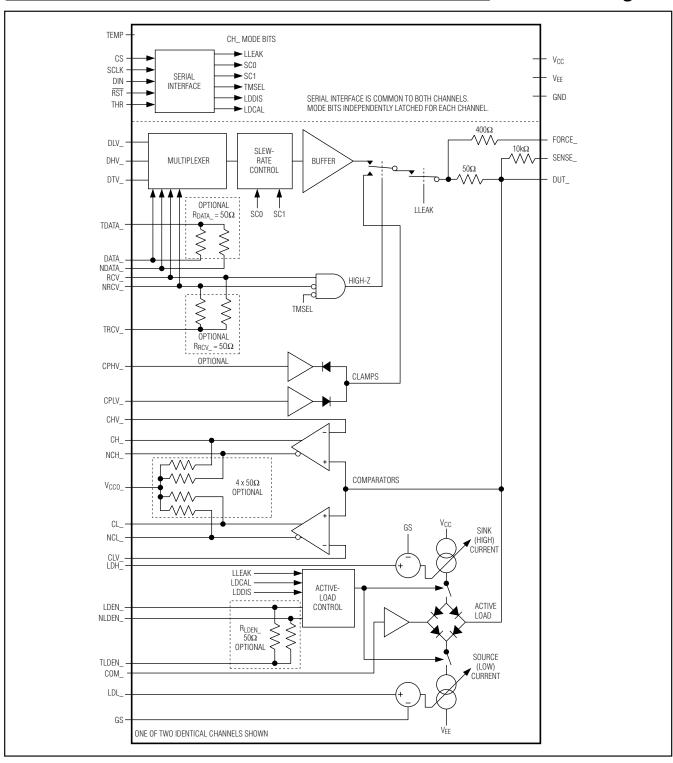
The MAX9967A provides tight matching of gain and offset for the drivers and offset for the comparators and active load, allowing reference levels to be shared across multiple channels in cost-sensitive systems. Use the MAX9967B for system designs that incorporate independent reference levels for each channel. Optional internal resistors at the high-speed inputs provide compatibility with ECL, LVPECL, LVDS, and GTL interfaces. Connect the termination voltage inputs (TDATA\_, TRCV\_, TLDEN\_) to the appropriate voltage for terminating ECL, LVPECL, GTL, or other logic. Leave the inputs unconnected for 100 $\Omega$  differential LVDS termination. In addition, ECL/LVPECL or flexible open-collector outputs with optional internal pullup resistors are available for the comparators. These features significantly reduce the discrete component count on the circuit board.

A 3-wire, low-voltage, CMOS-compatible serial interface programs the low-leakage, load-disable, slew-rate, and tri-state/terminate operational configurations of the MAX9967.

#### **Output Driver**

The driver input is a high-speed multiplexer that selects one of three voltage inputs: DHV\_, DLV\_, or DTV\_. This switching is controlled by high-speed inputs DATA\_ and RCV\_ and mode control bit TMSEL (Table 1). A slew-rate circuit controls the slew rate of the buffer input. Select one of four possible slew rates according to Table 2. The speed of the internal multiplexer sets the 100% driver slew rate (see the Driver Large-Signal Response graph in the *Typical Operating Characteristics*).

#### **Functional Diagram**



DUT\_ can be toggled at high speed between the buffer output and high-impedance mode, or it can be placed into low-leakage mode (Figure 2, Table 1). In high-impedance mode, the clamps are connected. High-speed input RCV\_ and mode control bits TMSEL and LLEAK control the switching. In high-impedance mode, the bias current at DUT\_ is less than 1.5µA over the 0 to 3V range, while the node maintains its ability to track high-speed signals. In low-leakage mode, the bias current at DUT\_ is further reduced to less than 50nA, and signal tracking slows. See the Low-Leakage Mode, LLEAK section for more details.

The nominal driver output resistance is  $50\Omega$ . Contact the factory for different resistance values within the  $45\Omega$  to  $51\Omega$  range.

#### **Clamps**

Configure the voltage clamps (high and low) to limit the voltage at DUT\_ and to suppress reflections when the channel is configured as a high-impedance receiver. The clamps behave as diodes connected to the outputs of high-current buffers. Internal circuitry compensates for the diode drop at 1mA clamp current. Set the clamp voltages using the external connections CPHV\_ and CPLV\_. The clamps are enabled only when the driver is in the high-impedance mode (Figure 2). For transient suppression, set the clamp voltages to approximately the minimum and maximum expected

DUT\_ voltage range. The optimal clamp voltages are application specific and must be empirically determined. If clamping is not desired, set the clamp voltages at least 0.7V outside the expected DUT\_ voltage range; overvoltage protection remains active without loading DUT\_.

#### **Comparators**

The MAX9967 provides two independent high-speed comparators for each channel. Each comparator has one input connected internally to DUT\_ and the other input connected to either CHV\_ or CLV\_ (see the Functional Diagram). Comparator outputs are a logical result of the input conditions, as indicated in Table 3.

Three configurations are available for the comparator differential outputs to ease interfacing with a wide variety of logic families. An open-collector configuration switches an 8mA current source between the two outputs. This configuration is available with and without internal termination resistors connected to  $V_{CCO}$  (Figure 3). For open-collector versions without internal termination, leave  $V_{CCO}$  unconnected and add the required external resistors. These resistors are typically  $50\Omega$  to the pullup voltage at the receiving end of the output trace. Alternate configurations may be used, provided that the *Absolute Maximum Ratings* are not exceeded. For open-collector versions with internal termination, connect  $V_{CCO}$  to the desired  $V_{OH}$  voltage.

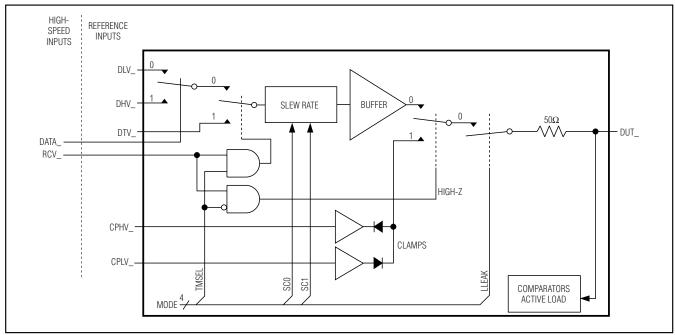


Figure 2. Simplified Driver Channel

Table 1. Driver Logic

1	RNAL CTIONS	INTEI CON REGI		DRIVER OUTPUT	
DATA_	RCV_	TMSEL	LLEAK		
1	0	Χ	0	Drive to DHV_	
0	0	Χ	0	Drive to DLV_	
Х	1	1	0	Drive to DTV_ (term mode)	
Х	1	0	0	High-impedance (high-z) mode	
Х	Χ	Χ	1	Low-leakage mode	

**Table 2. Slew-Rate Logic** 

SC1	SC0	DRIVER SLEW RATE (%)			
0	0	100			
0	1	75			
1	0	50			
1	1	25			

Each output provides a nominal 400mV<sub>P-P</sub> swing and  $50\Omega$  source termination.

An open-emitter configuration is also available (Figure 4). Connect an external collector voltage to VCCO\_ and add external pulldown resistors. These resistors are typically  $50\Omega$  to VCCO\_ - 2V at the receiving end of the output trace. Alternate configurations may be used provided that the <code>Absolute Maximum Ratings</code> are not exceeded.

#### **Active Load**

The active load consists of linearly programmable source and sink current sources, a commutation buffer, and a diode bridge (see *Functional Diagram*). Analog reference inputs LDH\_ and LDL\_ program the sink and source currents, respectively, within the 0 to 35mA range. Analog reference input COM\_ sets the commutation buffer output voltage. The source and sink naming convention is referenced to the device under test. Current out of the MAX9967 constitutes sink current and current into the MAX9967 constitutes source current.

The programmed source (low) current loads the device under test when  $V_{DUT}$  >  $V_{COM}$ . The programmed sink (high) current loads the device under test when  $V_{DUT}$  <  $V_{COM}$ .

The GS input allows a single level-setting DAC, such as the MAX5631 or MAX5734, to program the MAX9967's active load, driver, comparator, and clamps. Although all of the DAC levels are typically offset by VGS, the operation of the MAX9967's ground-sense input nullifies this offset with respect to the active-load currents. Connect GS to the ground reference used by the DAC. (VLDL\_ - VGS) sets the source current by +10mA/V. (VLDH\_ - VGS) sets the sink current by -10mA/V.

The high-speed differential input LDEN\_ and 3 bits of the control word (LDCAL, LDDIS, and LLEAK) control the load (Table 4). When the load is enabled, the internal source and sink current sources connect to the diode bridge. When the load is disabled, the internal current sources shunt to ground and the top and bottom of the bridge float (see the *Functional Diagram*). LLEAK places the load in low-leakage mode. LLEAK overrides LDEN\_, LDDIS, and LDCAL. See the *Low-Leakage Mode, LLEAK* section for more detailed information.

#### LDDIS and LDCAL

In some tester configurations, the load enable is driven with the complement of the driver high-impedance signal (RCV\_), so disabling the driver enables the load and vice versa. The LDDIS and LDCAL signals disable and enable the load independently of the state of LDEN\_. This allows the load and driver to be simultaneously enabled and disabled for diagnostic purposes (Table 4).

#### Low-Leakage Mode, LLEAK

Asserting LLEAK through the serial port or with RST places the MAX9967 into a very low-leakage state (see the *Electrical Characteristics*). The comparators function at full speed, but the driver, clamps, and active load are disabled. This mode is convenient for making IDDQ and PMU measurements without the need for an output disconnect relay. LLEAK is programmed independently for each channel.

When DUT\_ is driven with a high-speed signal while LLEAK is asserted, the leakage current momentarily increases beyond the limits specified for normal operation. The low-leakage recovery specification in the *Electrical Characteristics* table indicates device behavior under this condition.

**Table 3. Comparator Logic** 

DUT_ > CHV_	DUT_ > CLV_	CH_	CL_
0	0	0	0
0	1	0	1
1	0	1	0
1	1	1	1

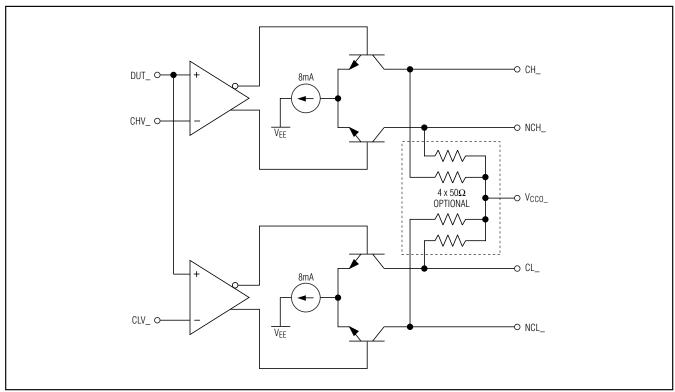


Figure 3. Open-Collector Comparator Outputs

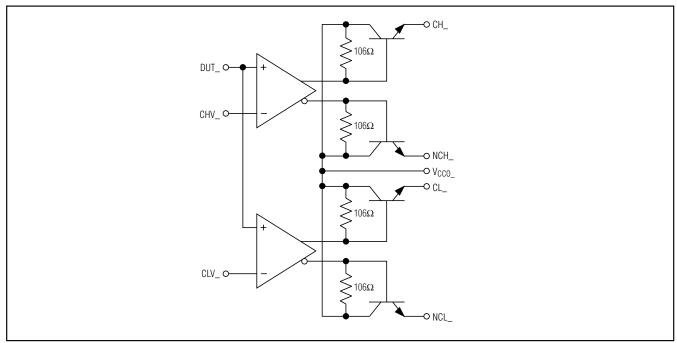


Figure 4. Open-Emitter Comparator Outputs

**Table 4. Active Load Programming** 

EXTERNAL CONNECTIONS	INTERNAL CONTROL REGISTER			MODE	
LDEN_	LDCAL	LDDIS	LLEAK		
0	0	0	0	Normal operating mode, load disabled	
1	0 0 0		0	Normal operating mode, load enabled	
X	1	0	0	Load enabled for diagnostics	
X	Χ	1	0	Load disabled	
X	X X 1		1	Low-leakage mode	

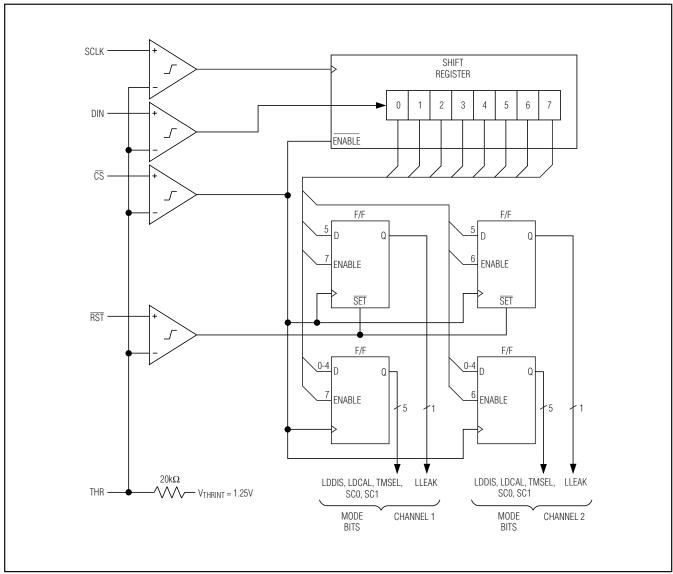


Figure 5. Serial Interface

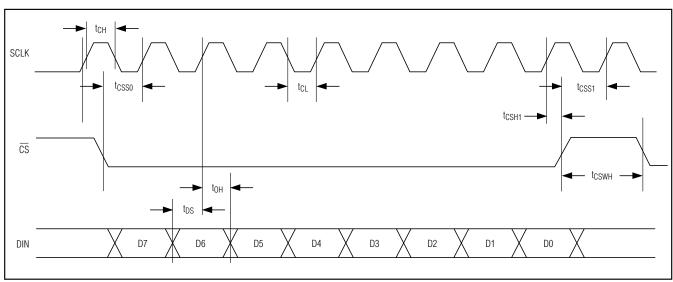


Figure 6. Serial-Interface Timing

#### **Serial Interface and Device Control**

A CMOS-compatible serial interface controls the MAX9967 modes (Figure 5). Control data flow into an 8-bit shift register (MSB first) and are latched when  $\overline{\text{CS}}$  is taken high, as shown in Figure 6. Latches contain 6 control bits for each channel of the dual pin driver. Data from the shift register are loaded to either or both of the latches as determined by bits D6 and D7, and indicated in Figure 5 and Table 5. The control bits, in conjunction with external inputs DATA\_ and RCV\_, manage the fea-

tures of each channel, as shown in Tables 1 and 2. RST sets LLEAK = 1 for both channels, forcing them into low-leakage mode. All other bits are unaffected. At power-up, hold RST low until VCC and VEE have stabilized.

Analog control input THR sets the threshold for the input logic, allowing operation with CMOS logic as low as 0.9V. Leaving THR unconnected results in a nominal threshold of 1.25V from an internal reference, providing compatibility with 2.5 to 3.3V logic.

Table 5. Shift-Register Functions

BIT	NAME	DESCRIPTION
D7	CH1	Channel 1 Write Enable. Set to 1 to update the control byte for channel 1. Set to 0 to make no changes to channel 1.
D6	CH2	Channel 2 Write Enable. Set to 1 to update the control byte for channel 2. Set to 0 to make no changes to channel 2.
D5	LLEAK	Low-Leakage Select. Set to 1 to put driver, load, and clamps into low-leakage mode. Comparators remain active in low-leakage mode. Set to 0 for normal operation.
D4	TMSEL	Driver Termination Select. Set to 1 to force the driver output to the DTV_ voltage when RCV_ = 1 (term). Set to 0 to place the driver into high-impedance mode when RCV_ = 1 (high-Z). See Table 1.
D3	SC1	Driver Slew-Rate Select. SC1 and SC0 set the driver slew rate. See Table 2.
D2	SC0	Driver Siew-Rate Select. Sc r and Sco set the driver siew rate. See Table 2.
D1	LDDIS	Load Disable. Set LDDIS to 1 to disable the load. Set to 0 for normal operation. See Table 4.
D0	LDCAL	Load Calibrate. Overrides LDEN to enable load. Set LDCAL to 1 to enable load. Set LDCAL to 0 for normal operation. See Table 4.

#### **Temperature Monitor**

The MAX9967 supplies a temperature output signal, TEMP, that asserts a nominal output voltage of 3.43V at a die temperature of +70°C (343K). The output voltage increases proportionately with temperature.

#### Heat Removal

Under normal circumstances, the MAX9967 requires heat removal through the exposed pad by use of an external heat sink. The exposed pad is electrically at VEE potential, and must be either connected to VEE or isolated.

Power dissipation is highly dependent upon the application. The *Electrical Characteristics Table* indicates power dissipation under the condition that the source and sink currents are programmed to 0mA. Maximum dissipation occurs when the source and sink currents are both at 35mA, the V<sub>DUT</sub> is at an extreme of the voltage range (-1.5V or +6.5V), and the diode bridge is fully commutated. Under these conditions, the additional power dissipated (per channel) is:

If the DUT is sourcing current,  $\Delta PD = (VDUT_ - VEE) \times ISOURCE + (VCC - VEE) \times ISINK.$ 

If the DUT is sinking current,  $\Delta P_D = (V_{CC} - V_{DUT}) \times I_{SINK} + (V_{CC} - V_{EE}) \times I_{SOURCE}$ 

The DUT sources the programmed (low) current when  $V_{DUT} > V_{COM}$ . The path of the current is from the DUT through the outside of the diode bridge and the source (low) current source to VEE. The programmed sink current flows from  $V_{CC}$  through the sink (high) current source, the inside of the diode bridge, and the commutation buffer to VEE.

The DUT sinks the programmed (high) current when  $V_{DUT} < V_{COM}$ . The path of the current is from  $V_{CC}$ 

through the sink (high) current source and the outside of the diode bridge to the DUT. The programmed source current flows from V<sub>CC</sub> through the commutation buffer, the inside of the diode bridge, and the source (low) current source to V<sub>EE</sub>.

Theta J-C of the exposed-pad package is very low, approximately 3°C/W to 4°C/W. Die temperature is thus highly dependent upon the heat-removal techniques used in the application.

Maximum total power dissipation occurs under the following conditions:

- $V_{CC} = +10.5V$
- VFF = -6.5V
- ISOURCE = ISINK = 35mA for both channels
- Load enabled
- $V_{DUT} = +6.5V$
- VCOM\_ < +5.5V</li>

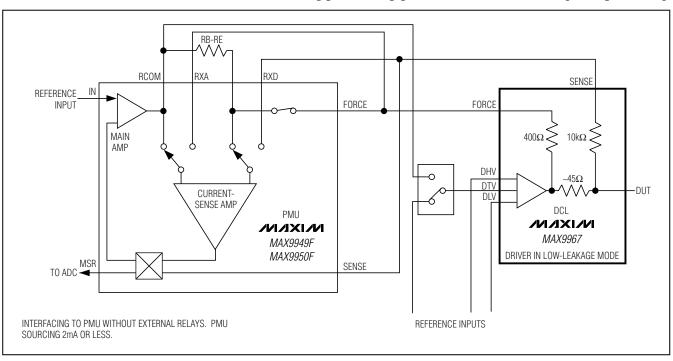
Under these extreme conditions, the total power dissipation is approximately 6W. If the die temperature cannot be maintained at an acceptable level under these conditions, use software clamping to limit the load output currents to lower values and/or reduce the supply voltages.

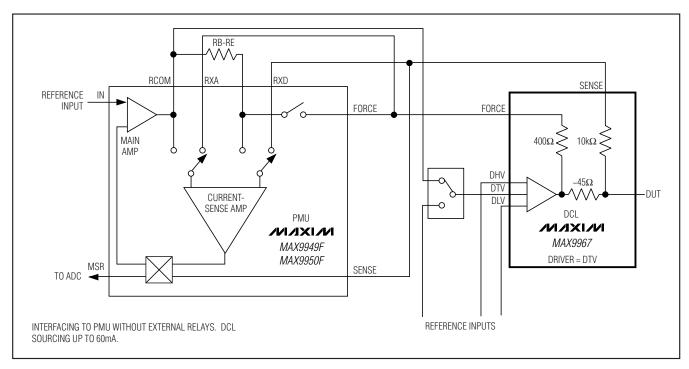
Chip Information

TRANSISTOR COUNT: 5656

PROCESS: Bipolar

### **Typical Application Circuits (Simplified)**



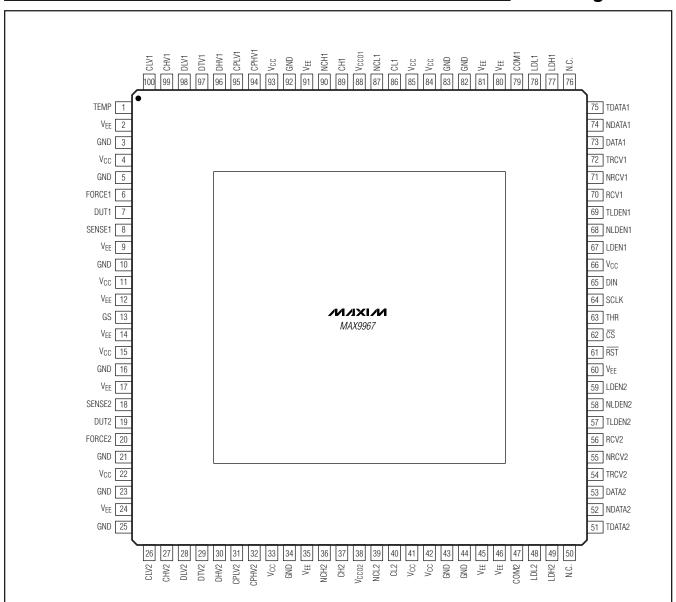


\_\_\_\_\_\_\_/N/1XI/W

### Selector Guide

PART	ACCURACY GRADE	COMPARATOR OUTPUT TYPE	COMPARATOR OUTPUT TERMINATION	HIGH-SPEED DIGITAL INPUT TERMINATION			HEAT EXTRACTION
	GIADE			RCV_	DATA_	LDEN_	EXTRACTION
MAX9967ADCCQ	А	Open collector	None	None	None	None	Тор
MAX9967AGCCQ	А	Open collector	None	100	100	100	Тор
MAX9967ALCCQ	А	Open collector	50Ω to V <sub>CCO</sub> _	100	100	100	Тор
MAX9967AMCCQ	А	Open emitter	ECL/LVPECL	None	None	None	Тор
MAX9967AQCCQ	А	Open emitter	ECL/LVPECL	100	100	100	Тор
MAX967ARCCQ	А	Open collector	50Ω to V <sub>CCO</sub> _	None	100	100	Тор
MAX9967BDCCQ	В	Open collector	None	None	None	None	Тор
MAX9967BGCCQ	В	Open collector	None	100	100	100	Тор
MAX9967BLCCQ	В	Open collector	50Ω to V <sub>CCO</sub> _	100	100	100	Тор
MAX9967BMCCQ	В	Open emitter	ECL/LVPECL	None	None	None	Тор
MAX9967BQCCQ	В	Open emitter	ECL/LVPECL	100	100	100	Тор
MAX9967BRCCQ	В	Open collector	50Ω to V <sub>CCO</sub> _	None	100	100	Тор

#### Pin Configuration



### Package Information

For the latest package outline information, go to <a href="https://www.maxim-ic.com/packages">www.maxim-ic.com/packages</a>.

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 SN74ACT8990FN
 SN74ACT8997DW
 SN74BCT8244ADW

 SN74BCT8245ADW
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 SN74ABT8245DWG4
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 CD4007UBM96
 CD4007UBM96
 CD4007UBM96
 CD4007UBM96
 CD4007UBM9
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 SN74LVT8996PWR
 SN74LVTH182502APM
 SN74LVTH18502APM
 SN74LVTH18504APM

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 SN74LVTH18502APM
 SN74LVTH18504APM